## Search Notes



Application/Control	No.

10520310

Applicant(s)/Patent Under Reexamination

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Examiner

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Art Unit

2627

## **SEARCHED**

Class	Subclass	Date	Examiner

## **SEARCH NOTES**

Search Notes	Date	Examiner
searched class 369/13.13, 13.17, 13.18, 13.19 and 13.33 - text search	11/29/2007	HH
only (see search history printout) and also consulted primary Tan Dinh.		
Updated search.	07/24/2008	HH

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner

U.S. Patent and Trademark Office Part of Paper No.: 20080725